



Specific guidelines for comparisons and CMCs in Length

Andrew Lewis

National Physical Laboratory (NPL)

Chair CCL's WG-MRA

Bureau
♦ **I**nternational des
♦ **P**oids et
♦ **M**esures



Outline

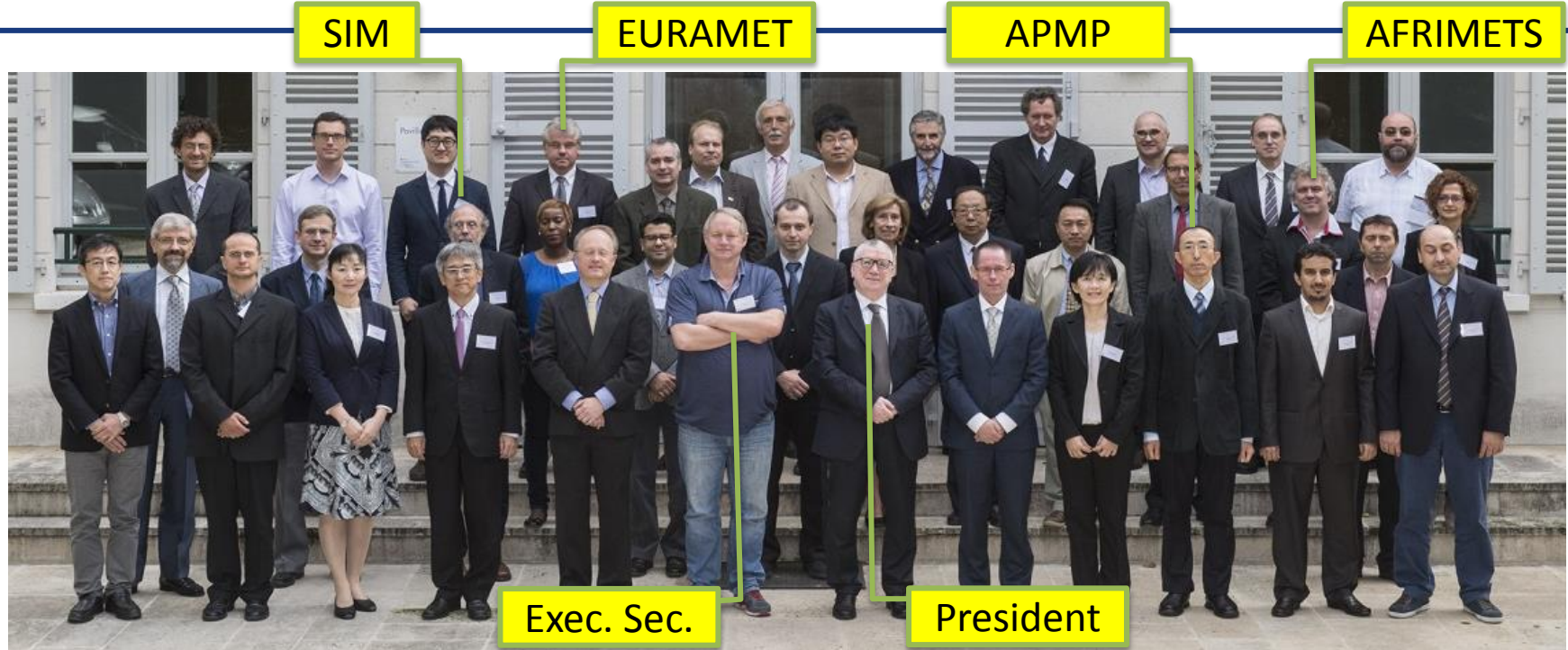
- ◆ Introduction to CCL & length metrology
- ◆ MRA: Organisational aspects within CCL
- ◆ MRA: Technical aspects within CCL
- ◆ Summary of key points

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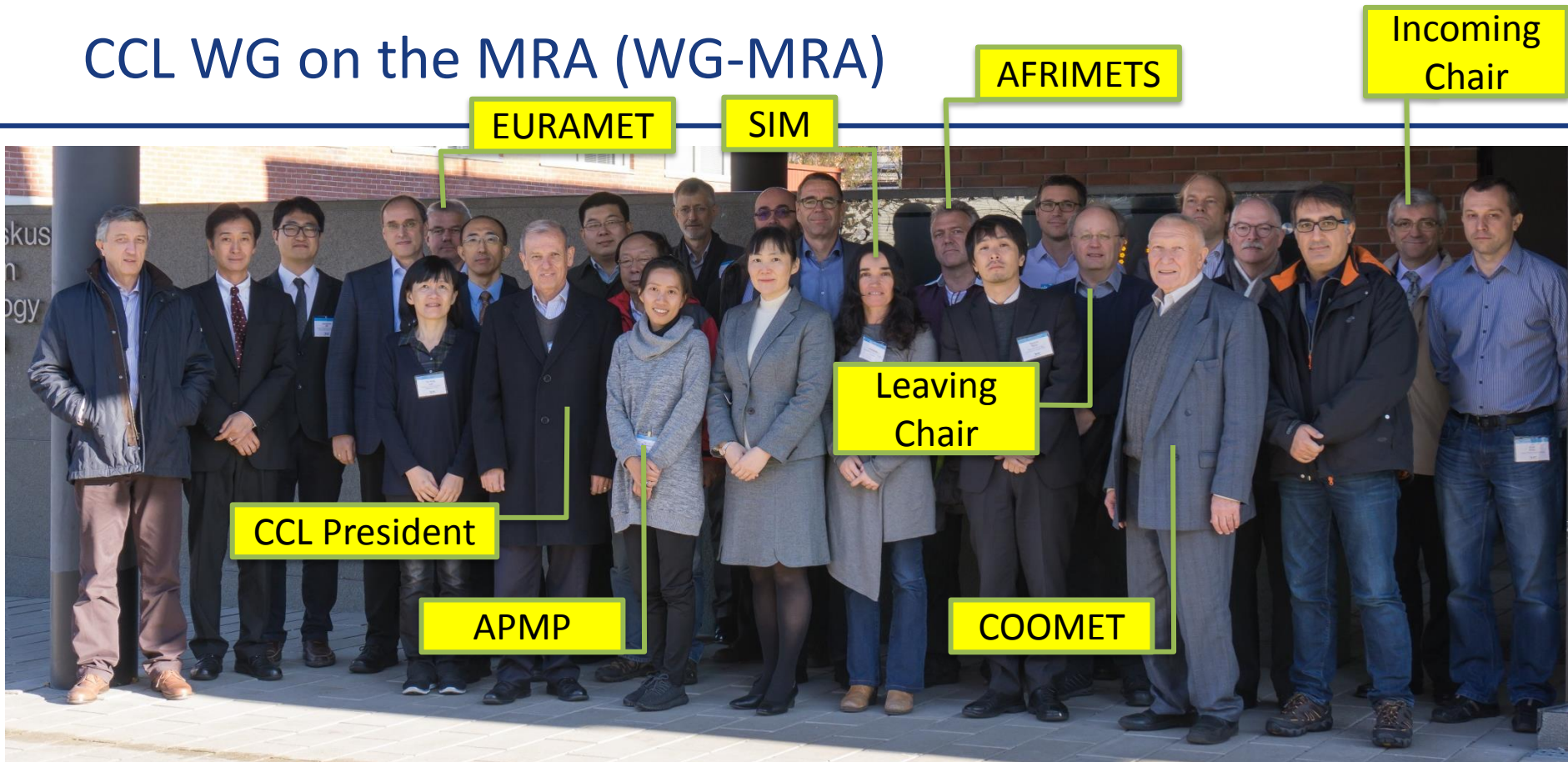


The CCL - formerly CCDM (Definition of the metre)



From the 16th meeting of the CCL (September 2015)

CCL WG on the MRA (WG-MRA)



Your important contacts in CCL !

RMO TC-L chairs

- | | | |
|------------|------------------------------------|--|
| – AFRIMETS | Oelof Kruger, NMISA (ZA) | oakruger@nmisa.org |
| – APMP | Jariya Buajarern, NIMT (TH) | Jariya@nimt.org.th |
| – COOMET | Aleksandr Kostrikov, NCM (UA) | alex_kost@ukr.net |
| – EURAMET | Harald Bosse, PTB (DE) | harald.bosse@ptb.de |
| – GULFMET | Ahmad Makinudin Dahlan, ESMA (UAE) | a.dahlan@qcc.abudhabi.ae |
| – SIM | Karina Bastida, INTI (AR) | bastida@inti.gob.ar |

Incoming WG-MRA chair

Alessandro Balsamo, INRIM (IT)	a.balsamo@inrim.it
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Length in a worldwide context – range of coverage

Geodetic-scale metrology

Large volume metrology

Coordinate metrology (3D)

Realization of the metre definition

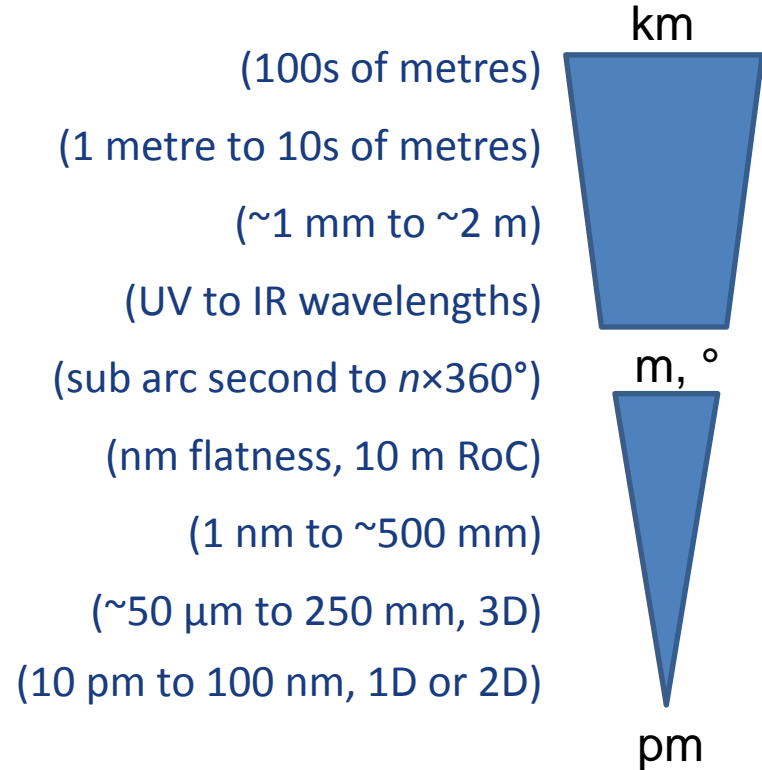
Angle metrology

***Classical* optical metrology**

Surface metrology (form, roughness)

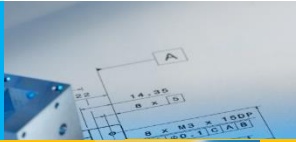
Micro-metrology

Dimensional nanometrology



Length in a worldwide context – areas of impact

Traceability in dimensional measurements underpins all manufacturing, engineering and assembly, ensuring interchangeability and the focus on



Precision engineering and dimensional metrology are key to three SI definitions based on fundamental constants: the Boltzmann constant, the Planck constant, and the elementary charge.



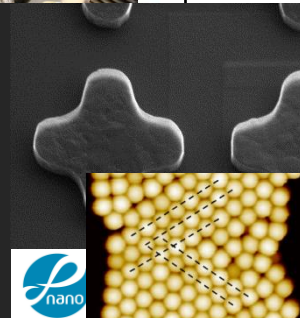
In aerospace, improving accuracy in aircraft assembly is reducing weight, reducing fuel burn (lower environmental impact, better energy efficiency). Accuracy up to 40 m



For new science (particle accelerators), energy generation (wind, civil nuclear), better accuracy and speed are needed and enabling longer life problems.



Surface form and texture are critical to many nano-scale devices, particularly for *in vivo* applications for health. Traceability infrastructure for 3D surface texture and simple dimensions on nano particles are focuses of the CCL and WG-Nano.

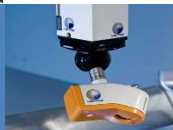


Length in a worldwide context – future challenges

Continue to improve access to and accuracy of, realizations of the metre via optical frequency standards



Support industry's transition to Industry 4.0 (faster and cheaper digital-based production)



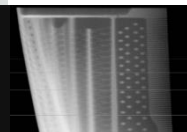
Develop and validate traceability routes for *in situ* metrology



Optimize length comparison portfolio to support new areas without increasing workload



Coordinate pre-normative research into novel coordinate metrology systems such as X-ray CT, micro CMMs



Extend the traceability to the metre to extreme scales: sub- nanometre and geodetic (kilometre)



MRA underpinning measurement & calibration

BIPM
Bureau International des Poids & Mesures

Home | Key and supplementary comparisons | Calibration and Measurement Capabilities - CMCs

KCDB home > Free search results

The BIPM key comparison database

Refine your search

CMC AREA
CMCs General Physics (5)

PHYSICS
Dimensional metrology (5)

GEOGRAPHIC LOCATION
EURAMET (5)
United Kingdom (5)

Result of the search
Your query 'gauge block' produced 5 results

[New search](#)

United Kingdom, NPL (National Physical Laboratory)
[Complete CMCs in Length for United Kingdom \(.PDF file\)](#)
End standards. Long gauge block: thermal expansivity, α , $9.00E-06$ 1/K to $1.30E-05$ 1/K
Absolute expanded uncertainty ($k = 2$, level of confidence 95%) in 1E-06/K: $(0.004 + 11/L + 0.000007L)$, L in mm
Absolute interferometry, exact fractions
Length: 100 mm to 1000 mm
Temperature: 18 °C to 25 °C
Internal NMI service identifier: NPL/17
End standards. Gauge block: central length L , 0.5 mm to 100 mm
Absolute expanded uncertainty ($k = 2$, level of confidence 95%) in nm: $Q[19, 0.21L]$, L in mm
Absolute interferometry, exact fractions
Approved on 03 August 2011
Internal NMI service identifier: NPL/10



BIPM
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Home | Key and supplementary comparisons | Calibration and Measurement Capabilities - CMCs

KCDB home > Free search results

The BIPM key comparison database

Refine your search

CMC AREA
CMCs General Physics (2)

PHYSICS
Dimensional metrology (2)

GEOGRAPHIC LOCATION
SIM (2)
United States (2)

Result of the search
Your query 'gauge blocks' produced 2 results

[New search](#)

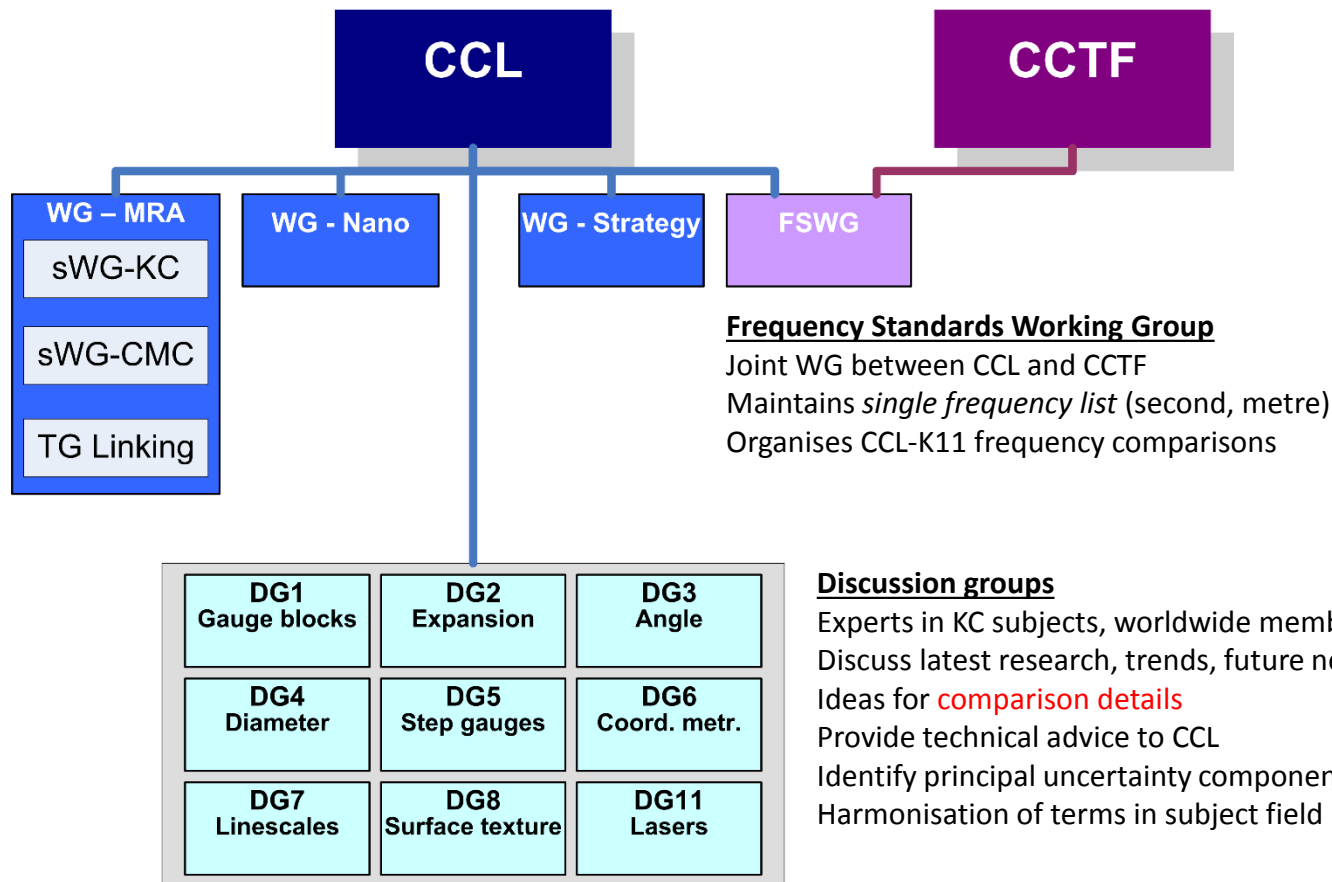
United States, NIST (National Institute of Standards and Technology)
[Complete CMCs in Length for United States \(.PDF file\)](#)
End standards. Gauge block: central length L , 0.1 mm to 100 mm
Absolute expanded uncertainty ($k = 2$, level of confidence 95%) in nm: $(18 + 0.15L)$, L in mm, values range from 18 mm to 33 mm
Interferometry, exact fractions
Internal NMI service identifier: NIST/3
End standards. Gauge block: central length L , 0.1 mm to 101.6 mm
Absolute expanded uncertainty ($k = 2$, level of confidence 95%) in nm: $(25 + 0.35L)$, L in mm, values range from 25 mm to 61 mm
Mechanical comparison to gauge block
Internal NMI service identifier: NIST/4



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- ◆ Introduction to CCL & length metrology
- ◆ **MRA: Organisational aspects within CCL**
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CCL organisation for MRA tasks



Working Group on the MRA

MRA delegated authority from CCL

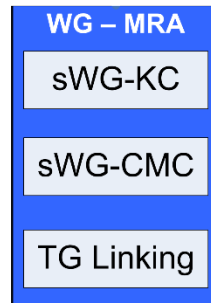
Formed of 2 sub-Working Groups:

- Key Comparisons
- CMCs

And a Task Group on Linking

Mostly *ex officio* membership

CCL organisation for MRA tasks



The majority of the MRA processes, decisions, approvals occur in WG-MRA

In 2012 CCL delegated the authority to approve key comparison protocols and reports to WG-MRA

WG-MRA reports to CCL on the work it has performed. WG-MRA meets yearly, CCL meets 3 yearly.

CCL WG-MRA

WG-MRA

Chair: **Balsamo**

sWG-KC

Chair: Lewis

sWG-CMC

Chair: de Oliveira

TG Linking

Chair: Thalmann

sWG-KC

- ♦ *RMO TC-L chairs*
- ♦ *DG Moderators*
- ♦ *KC pilots*

Organises comparisons

Approves protocols & reports

sWG-CMC

- ♦ *RMO TC-L chairs*

Looks at Executive Reports

Receives annual report from RMOs on

CMC actions: pending, taken, completed

TG Linking

- ♦ *6 named individuals*

Studies which comparisons can be linked

Suggests appropriate linking mechanism

WG-MRA

Formed from 2 WGs & TG-Linking & additional named members

Coordinates across both sub WGs

Plenary session and organisation of annual meeting

Produced a range of **guidance documents and CMC categorisation**

The 'DimVIM' – CMC categorisation list

- Designed September 1999
- Updated periodically (latest 2017)
- Master copy in English, but translated (& maintained) in:
 - Chinese, Czech, Finish, French, German, Greek, Japanese, Korean, Portuguese, Spanish, Turkish, Thai
- Version 10 (10/2017)

Ver. 10 (2017)

CLASS

Consultative Committee for Length – CCL

Working Group on the MRA – WG-MRA

CCL Length Services Classification (DimVIM)

English Language Approved Terms

CCL Service Category	Instrument or Artifact	Measurand(s)
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1 Radiations of the Mise en Pratique

1.1 Laser Radiations

1.1.1	frequency stabilized laser.	vacuum wavelength; optical frequency.
1.1.2	other stabilized laser.	vacuum wavelength; optical frequency.

1.2 Lamp Radiations

1.2.1	spectral lamp.	vacuum wavelength.
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2 Linear Dimensions

2.1 Length Instruments

2.1.1	(laser, length) interferometer (system, optics, refractometer).	error of indicated displacement; wavelength compensation.
2.1.2	EDM instrument.	error of indicated distance.
2.1.3	1-D measuring machine.	error of indicated [size; displacement].
2.1.4	height measuring instrument.	error of indicated [vertical size; displacement].
2.1.5	1-D displacement [transducer, actuator] (LVDT, PZT,...)	error of indicated displacement.
2.1.6	gauge block comparators	error of indicated displacement.
2.1.7	dial-indicator tester.	error of indicated displacement.

2.2 End Standards

2.2.1	gauge block.	central length; variation in length; thermal expansivity; length difference of gauge block pairs.
2.2.2	length bar (long gauge block).	central length; variation in length; thermal expansivity.

1 实现米的辐射		
1.1 激光辐射		
1.1.1	实现米的稳频激光.	真空波长; 光频
1.1.2	其他稳频激光	真空波长; 光频
1.2 灯辐射		
1.2.1	光谱灯	真空波长; 光频
2 线性尺寸		
2.1 长度仪器		
2.1.1	(激光, 长度) 干涉仪 (系统, 光学, 折射计).	位移示值误差; 波长补偿.
2.1.2	光电测距仪	距离示值误差
2.1.3	一维测量仪器	(尺寸, 位移) 示值误差
2.1.4	高度仪器	(垂直尺寸, 位移) 示值误差
2.1.5	一维位移 [传感器, 发生器] (LVDT, PZT, ...)	位移示值误差
2.1.6	量块比较仪	位移示值误差
2.1.7	指示表检测仪	位移示值误差
2.2 端量标准器		
2.2.1	量块	中心长度; 长度变化量; 热膨胀
2.2.2	长度棒 (长量块).	中心长度; 长度变化量; 热膨胀

9 CCL Guidance documents on comparisons & CMCs

Document	Title
<u>CCL-WG/-MRA-GD-1</u>	Running of MRA comparisons in length metrology and monitoring their impact on CMCs
<u>CCL-WG/-MRA-GD-2</u>	CCL comparison scheme
<u>CCL-WG/-MRA-GD-3</u>	Guide to preparation of Key Comparison Reports in Dimensional Metrology
<u>CCL-WG/-MRA-GD-3.1</u>	Comparison technical protocol template
<u>CCL-WG/-MRA-GD-3.2</u>	Comparison report template
<u>CCL-WG/-MRA-GD-3.2b</u>	Template bilateral report
<u>CCL-WG/-MRA-GD-3.3</u>	Executive Report Template
<u>CCL-WG/-MRA-GD-4</u>	KC planning [frequently updated] – timeline/scheduling
<u>CCL-WG/-MRA-GD-5</u>	Guide to formatting CMC entries v2

Comparison portfolio: choosing what & how many

Principal Techniques	CCL-K1	CCL-K2	CCL-K3	CCL-K4	CCL-K5	CCL-K6	CCL-K7	CCL-K8
	gauge block	length bar	poly gau.	diameter	ball step	2D CMM	linescale	surf tex.
Realizing the Metre definition								
Interferometry	2	2		2	2	2	2	1
Wavelengths in air	2	2		2	2	2	2	1
Gauge Issues								
Temperature of Gauge	1	2		2	2	2	2	1
Mounting & Aligning	1	2	2	2	2	2	2	1
Wavefront Probing								
Reflection Phase Effects	2	1						
Wringing	2	1						
Mechanical Probing								
Stylus contacting at surface, 1-D				2	1 2	1		2
Bi-directional probing for size				2	2			
Probing for 3-D center coordinates					2	2		
Image Probing								
Sensing Line Centres							2	
Angle Metrology								
Measuring small angles (autocoll.)			1 2					
Large Angle Gen: Circle Dividers			2 1			1		
Small Angle Gen: SineBar, CircDiv.			2					
Formal mathematical processing of data sets								
ISO parameter extraction								2
Form Metrology								
Flatness								1
Roundness				1				
Thread, Gear Profile								
3-D Surface								1

Most CMCs are based around classes of artefact (& lasers – later)

Too many artefacts for one comparison each

Looked at key skills needed to perform length metrology at the highest level

Used these to reduce number of artefacts and hence limit number of comparisons

Table comes from CCL Strategy Document

2 = strong test of skill by comparison
 1 = weaker test of skill
 0 = no link

Comparison portfolio: participation

- ◆ Strike a balance on number of participants

More participants

- ◆ Ensure inter-RMO linking
- ◆ Robustness against problems/withdrawals
- ◆ Fewer comparisons overall
- ◆ Better accuracy KCRV

Fewer participants

- ◆ Shorter duration (less time for pilot)
- ◆ Results available sooner
- ◆ Reduced artefact wear (*)
- ◆ Easier to coordinate

(*) High quality artefacts normally calibrated on 2 to 3 year interval.
In a comparison, they are calibrated every month for 1.5 to 2 years.
Some artefacts are no longer measurable at the end...

2 comparison schemes: *classical, inter-RMO*

- ◆ Response to **criticism** from CCL members of **workload**
- ◆ CCL comparison then RMO comparison: **double work**
- ◆ Worse for smaller RMOs – few CCL members, always have double workload
- ◆ RMO TC chairs agreed to **share duties across regions**
- ◆ ***Inter-RMO*** comparisons: multiple RMOs in one comparison
- ◆ No CCL comparison unless necessary
- ◆ Retain ***classical*** organisation (CCL then RMO) for **large circulation** comparisons in popular topics (*e.g.* gauge blocks K1, diameter K4)
- ◆ Inter-RMO comparisons for other topics *e.g.* step gauges (K5)

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If required, a virtual CCL comparison may be formed for analysis purposes by the CCL members which take part.

- It guarantees equal status of CCL and RMO comparisons.
- It provides more flexibility in grouping laboratories of different regions in order to achieve comparisons of similar size and to run comparisons with adequate artefacts at different levels of uncertainty.
- It allows for an optimized and possibly reduced number of comparisons, and consequently requires lower expenses for purchasing suitable artefacts, fewer pilot laboratories and reduced workload for CCL members.
- It gives more flexibility and more frequent opportunities for any laboratory to join a comparison when needed to support its CMCs.

CCL Key Comparison Portfolio

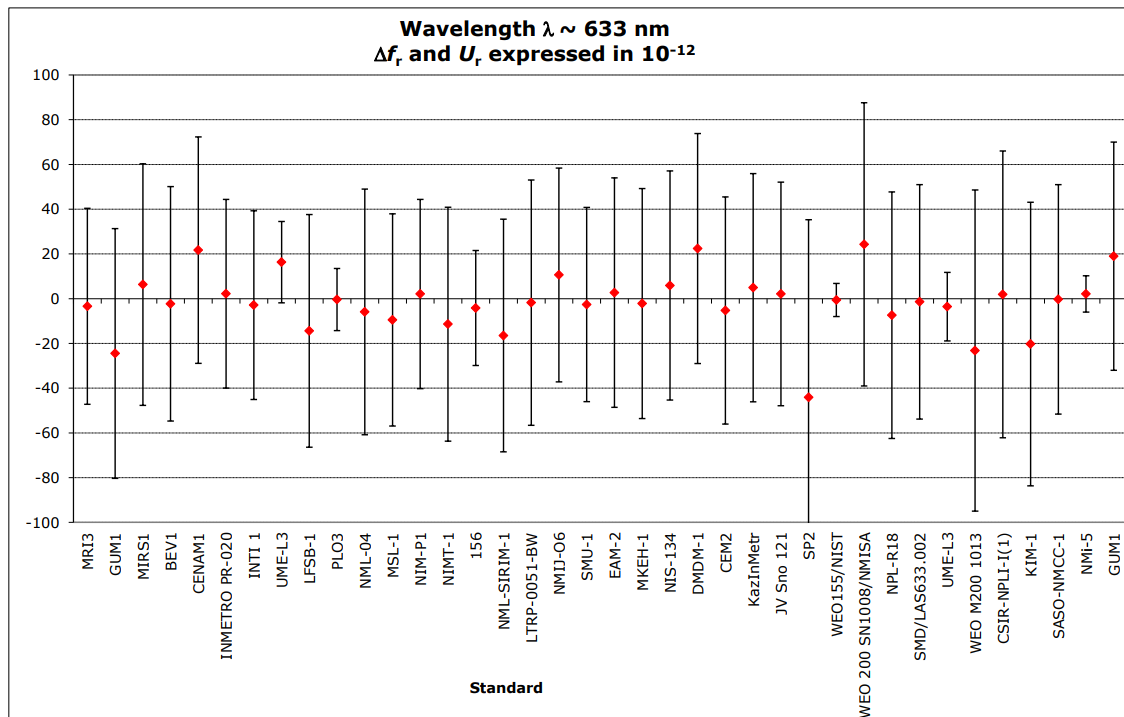
<u>No.</u>	<u>Artefact</u>	<u>Type</u>
◆ K1	gauge blocks	[classical]
◆ K2	long gauge blocks (merged into K1)	[classical]
◆ K3	angle	[classical]
◆ K4	diameter	[classical]
◆ K5	step gauges	[inter-RMO]
◆ K6	2D CMM artefacts (on hold after cycle 1, \$\$\$)	[inter-RMO]
◆ K7	linescales	[classical]
◆ K8	surface texture	[inter-RMO]
◆ K11	lasers (yearly ongoing participation)	[classical]

Comparison frequency

- ◆ Originally tried to achieve **7 year repeat cycle** but difficult to conclude all comparisons within this period.
- ◆ Changed to **10 year cycle** which is being **achieved**.
- ◆ WG-MRA has the task to organise comparisons with a view to offering participation to all CCL members at least once every 10 years.
- ◆ WG-MRA also assists RMOs to achieve 10 year repeat (inter-RMO) by coordinating inter-RMO participation.
- ◆ Aim to **avoid bilateral comparisons** (big workload for reviewing reports, gains for only 2 or 3 participants).
- ◆ Allow 'stretch' of 10 year periodicity if new comparison cycle starting soon or comparison in another RMO will start soon.
- ◆ **2017 - Accepted APMP proposal for 'paid for/commercial calibrations' as reference values for NMI needing to urgently prove a CMC claim.**

Ongoing CCL comparison

- ◆ CCL-K11 – comparison of standard laser frequencies
- ◆ 5 node labs:
 - BEV, MIKES, NIMT, NMII, NPL
 - Doing the work previously offered by BIPM length section
- ◆ Protocol being rewritten – not really like a comparison



Progress: 116 comparisons, 88 completed

Comparison totals complete/run

BIPM	02/02	
CCL-K	07/10	(3 in running cycle 2)
CCL-S	04/04	
AFRIMETS-K	00/01	(starting)
AFRIMETS-S	01/03	
APMP-K	09/12	(3 running in cycle 2)
APMP-S	05/08	
COOMET-K	01/01	
COOMET-S	16/20	
EURAMET-K	12/19	(4 running in cycle 2)
EURAMET-S	23/26	
GULFMET-K	00/00	
GULFMET-S	00/01	(starting first ever)
SIM-K	04/05	
SIM-S	04/04	

Summary of progress on all length comparisons																
Identifier	REGISTRATION			PROTOCOL		MEASUREMENTS			REPORTING		REPORT APPROVALS		KCDB ENTRY		EXEC. REPORT	
	Comparison proposed (BMO, CCU)	Comparison accepted (CCU)	Registration with KCDB	Protocol submitted to WGM for approval	Protocol approved by WGM	Start of artefact circulation	End of artefact circulation	Final results received	Start of report to participants only	Start of report to participants	Final report approved by WGM	Final report approved by NMA	Final report sent to KCDB	Final report sent to KCDB	Executive report prepared and sent to CCU, NMA for publication	Executive report finished and sent to CCU, Exec. Sec. for website storage
BIPM.L-K10	1988	1988	Y	Y	Y	1988	2000	Y	Y	Y	Y	Y	Y	Y	N/A	N/A
BIPM.L-K11	2004	2004	Y	Y	Y	2004	2006	Y	Y	Y	Y	Y	Y	Y	N/A	N/A
CCL-K1	Sep-97	Sep-97	Y	Y	N	Mar-98	Sep-99	Y	Sep-99	01-Jan	Sep-00	Sep-00	Y	Y	N	N
CCL-K1.2011	Sep-09	Sep-99	Y	Jun-10	Sep-09	2011	Jun-13	Y	exp 11/2014							
CCL-K2	Sep-97	Sep-97	Y	Y	N	Sep-99	Aug-01	Y	Sep-01	Y	Mar-03	Sep-03	Y	Y	Sep-03	Y
CCL-K3	Sep-97	Sep-97	Y	Y	N	Jul-00	Aug-02	Y	Y	Y	Aug-07	Sep-07	Y	2008/9	Y	Y
CCL-K3.2016	CCL 2015															
CCL-K4	Sep-97	Sep-97	Y	Y	N	Nov-00	Dec-02	Y	Jul-03	Jul-05	Jan-07	Sep-07	Y	Y	Aug-07	Y
CCL-K4.2014	Oct-14	Oct-14	06/10/2015	Aug-15	Sep-15	Aug-15	exp 3/17									
CCL-K5	Sep-97	Sep-97	Y	Y	N	Apr-99	Mar-02	Y	Y	Jul-03	Sep-03	May-05	Y	Y	Sep-03	Y
CCL-K6	Sep-97	Sep-97	Y	Y	N	Feb-01	Aug-04	Y	Jul-06	May-07	Oct-08	Sep-09	2009	2009	Mar-13	Nov-14
CCL-K11	2011	2011	Y	Y	N	2011	ongoing	-	-	-	-	-	-	-	-	-
CCL-S1	Jun-98	Jun-98	Y	N/A	N/A	Feb-99	Jun-00	Y	Y	Nov-00	Nov-00	Y	Y	N/A	N	N
CCL-S2	Jun-98	Jun-98	Y	N/A	N/A	Sep-00	Jul-02	Y	Y	Feb-03	Aug-03	Sep-03	Y	N/A	Jul-03	Y
CCL-S3	Jun-98	Jun-98	Y	N/A	N/A	May-00	Apr-02	Y	Y	Aug-03	Aug-03	Sep-03	Y	N/A	N	N
CCL-S4	Jun-98	Jun-98	Y	N/A	N/A	Jan-05	Mar-06	Y	Y	Oct-07	Mar-08	2008/9	2008/9	N/A	N	N
AFRIMETS.L-K1																
SADCMET.L-S1	Y	Y	Y	N/A	N/A	2007										
SADCMET.L-S2	Y	Y	Y	N/A	N/A											
AFRIMETS.L-S3	Y	Y	Y	N/A	N/A	Nov-12	May-13	Y	Y	Y	15/04/2015	06/05/2015	17/08/2015	N/A	N	N
AFRIMETS.L-S4	Y	Y	Y	N/A	N/A	Aug-12	Y	Y								
APMP.L-K1	Aug-98	Y	Y	N	N	Jan-01	Jul-02	Y	Y	Y	Mar-05	Sep-05	Y	Y	N	N
APMP.L-K1.1	Oct-04	Y	Y	N	N	May-05	Aug-06	Y	Y	Y	Jul-09	Sep-09	Y	Y	N	N
APMP.L-K1.1.2011	Y	Y	Y	N	N	2011	Dec-12	Y	Feb-12	Y	13/02/2013	22/04/2013	11/04/2013	22/04/2013	21/11/2013	
APMP.L-K2	Aug-98	Y	Y	N	N	May-00	Apr-03	Y	Y	Y	Dec-03	Y	Dec-03	Dec-03	Mar-08	Y
APMP.L-K3	Y	Y	Y	N	N	2005	2007	Y	Y	exp 11/2014	18/07/2016	#####	23/08/2016	N		
APMP.L-K4	Y	Y	Y	N	N	2008	Y	Y	2012	Nov-13	15/05/2014	18-Jun-14	18-Jun-14	17/07/2014	16/02/2015	06/05/2015
APMP.L-K5.2006	2003	Y	Y	N	N	2006	2010	Y	Y	Nov-10	11/03/2011	Oct-11	Jan-11	N	07/03/2013	11/04/2013
APMP.L-K5.2006.1	22/08/2012	Y-RMO	22/08/2012	N	N	27/08/2012	Y	Y	Y	Dec-14	16/10/2016					
APMP.L-K5.2014	Y	Y	26/11/2014	03/12/2014	12/12/2014	15/12/2014			due 11/2015							
APMP.L-K6	Oct-05	Y	Y	N	N	2008	2008	Y	Y	Y	22/01/2014	11-Feb-14	10-Jul-14	N	01/09/2015	23/09/2015

Current & future comparisons

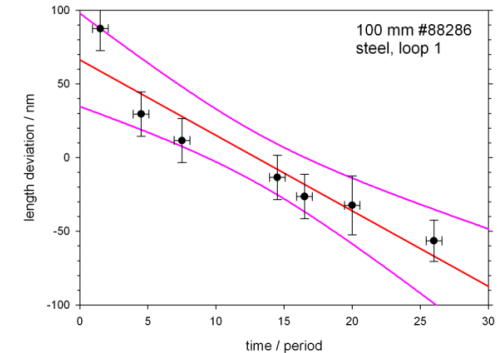
<u>No.</u>	<u>Artefact</u>	
◆ K1	gauge blocks	AFRIMETS planning, CCL 2021
◆ K3	angle	CCL 2017 planning
◆ K4	diameter	CCL & EURAMET running, CCL 2026
◆ K5	step gauges	EURAMET ending, APMP 2025?
◆ K7	linescales	CCL planning
◆ K8	surface texture	APMP 2019, EURAMET 2021
◆ K11	lasers	(yearly ongoing participation)

CCL Pilot Studies

- ◆ Some pilot studies in nanometrology were re-classified as CCL supplementary comparisons – no longer allowed to do so!
 - CCL-S1 – one dimensional nano gratings
 - CCL-S2 – step height standards
 - CCL-S3 – line scale standards
 - CCL-S4 – two-dimensional gratings
- ◆ Several pilot studies in the RMOs were *post hoc* elevated to be RMO supplementary comparisons – this is no longer allowed also!

Specifics of CCL KC protocols

- ◆ Usual items: participants, timetable, artefacts, SI traceability,
 - ◆ Insurance for artefact(s)
 - ◆ How to handle/transport (often include thermal logger)
 - ◆ Definition of measurand(s), reference conditions (*e.g.* ISO 1: 20 °C)
 - ◆ How to report results (preferred units)
 - ◆ Reporting timescale (max 6 weeks)
 - ◆ How the KCRV will be calculated (usually weighted mean)
 - ◆ Potential datafitting for artefact instability (confirm drift, model drift)
 - ◆ Correlation between participants
 - ◆ Main uncertainty contributions
 - ◆ Request for 'no extreme' measures
 - ◆ One or two loops and linking
-
- ◆ WG-MRA approves all key comparison protocols - including RMO ones



Traveling standards – length artefacts

- ◆ Use *normal* artefacts
 - Ideally with stability history
 - Occasionally trial novel artefacts
 - Have used an instrument (autocollimator)
- ◆ Artefacts often become damaged
 - Sometime multiples/backups needed
- ◆ Accelerated wear rate
 - Can be issue for last participants – see most damaged items
- ◆ Protection for transport
 - Early days – hand transport in aircraft cabins



Comparison reports – Final & Executive

Process

- ◆ GD-3.2 Report Template
- ◆ GD-3.2b Bilateral report Template
- ◆ GD-3.3 Executive Report Template
- ◆ **Draft A** (Excel file of results) – simple confirmation of data
- ◆ **Draft B** contains first analysis
 - iterated until concluded then becomes **Final Report**
- ◆ **Final** sent to WG-MRA for discussion and approval
- ◆ **Executive Report** follows soon (private)
 - Simplest summary of main results (usually DoE and U(Doe))
 - Comparison of uncertainty with relevant CMCs – good/bad
 - Contains CMC actions and any outcomes so far
 - Copied to Exec. Sec (to website), copied to RMO TC-L chairs

Pragmatism vs strict rules

- ◆ Results changeable to **before Draft A** with no concern (ideally reason given), no comment in report
- ◆ **After Draft A** correction of obvious **blunders** caused by ‘comparison intricacies’ (noted in report)
- ◆ **Technical revision** of results with clear justification and approval of participants (detailed note in report, calculation before and after) – prevents bilateral
- ◆ CMC action – has to be agreed by RMO TC-L as appropriate and signed off by them:
 - Greying out of CMC
 - Increase uncertainty in CMC
 - Voluntary withholding of service
 - Internal comparison evidence
 - Informal bilateral

Review of CMCs in light of comparison results

- ◆ *Poor* results are investigated
- ◆ *Poor* means too many with $En \gg 1$ (En = 'difference'/'uncertainty')
- ◆ A few with $1 < En < 1.5$ may be OK (accreditors use same criterion)
- ◆ More than one with $En > 1.5$ not OK
- ◆ Described in detail in Executive Report
- ◆ Seek explanation, discuss, approve within RMO
- ◆ No solution, grey CMC, increase uncertainty, suspension, ?actions?
- ◆ Yearly report from RMO to sWG-CMC
- ◆ Lists of actions (action pending, action done, issue solved)
- ◆ **Unsolved issues – WG chair emails local TC-Q chair to investigate**

How to be a good pilot in CCL comparisons

- ◆ Use the template documents
- ◆ Register with RMO, KCDB, WG-MRA
- ◆ Accept extra-RMO participants (if needed)
- ◆ Get protocol approved by WG-MRA (detect errors, problems)
- ◆ Seek donation of artefacts
- ◆ Keep communicating
- ◆ Prepare outline analysis early- populate Excel file as results come in
- ◆ Draft A release within 1 week of final results (just the Excel file – check blunders)
- ◆ Draft B very soon after confirmation of Draft A
- ◆ Use existing analysis spreadsheets for KCRV, *En*, etc.
- ◆ Fully detailed Final Report (can be up to 70 pages!)
- ◆ Short and succinct Executive Report (ideally 4-6 pages) – with **recommendations on CMCs**

Outline

- ◆ Introduction to CCL & length metrology
- ◆ MRA: Organisational aspects within CCL
- ◆ **MRA: Technical aspects within CCL**
- ◆ Summary of key points

Key Comparison Reference Values

- ◆ Use weighted mean unless known issues (over-dominant NMI)
- ◆ Bilateral comparisons do not generate KCRV, just DoE, $U(\text{DoE})$
- ◆ Iterative process
 - Calculate KCRV (weighted mean of contributing results)
 - Calculate En values = $\text{DoE}/U(\text{DoE})$ taking '-' for correlation
 - Examine Birge ratio – consistent results?
 - If not, remove highest En result
- ◆ Re-calculate En for excluded results taking '+' in uncertainty
- ◆ Plot graphs, generate table of En
- ◆ For Executive Report, generate tables of DoE, $U(\text{DoE})$, $U(\text{CMC})$
- ◆ Do not calculate mutual DoE (12 participants, 50 measurands, ...6600 numbers...)

KCRV: the mathematics (1/2)

ITERATE BASED ON DECISION ON NEXT SLIDE

Compute the normalised weight, w_i , for each result x_i given by: $w_i = C \cdot \frac{1}{[u(x_i)]^2}$ where the normalising factor, C , is given by: $C = \frac{1}{\sum_{i=1}^I \left(\frac{1}{u(x_i)} \right)^2}$

Then calculate the weighted mean, \bar{x}_w , which is given by: $\bar{x}_w = \sum_{i=1}^I w_i \cdot x_i$

The uncertainty of the weighted mean is calculated by: $u(\bar{x}_w) = \sqrt{\frac{1}{\sum_{i=1}^I \left(\frac{1}{u(x_i)} \right)^2}} = \sqrt{C}$

After deriving the weighted mean and its associated standard uncertainty, the deviation of each laboratory's result from the weighted mean is determined simply as $x_i - \bar{x}_w$

The uncertainty of this deviation is calculated as a combination of the uncertainties of the result, $u(x_i)$, and the uncertainty of the weighted mean $u(\bar{x}_w)$

$$u(x_i - \bar{x}_w) = \sqrt{[u(x_i)]^2 - [u(\bar{x}_w)]^2}$$

KCRV: the mathematics (2/2)

For each iteration, check for consistency using *Birge Ratio*, R_B

$$R_B = \frac{u_{ext}(\bar{x}_w)}{u(\bar{x}_w)} \quad \text{where} \quad u_{ext}(\bar{x}_w) \text{ is the external standard deviation} \quad u_{ext}(\bar{x}_w) = \sqrt{\frac{1}{(I-1)} \cdot \frac{\sum_{i=1}^I w_i (x_i - \bar{x}_w)^2}{\sum_{i=1}^I w_i}}$$

The Birge ratio has an expectation value of $R_B = 1$, when considering standard uncertainties. For a coverage factor of $k = 2$, the expectation value is increased and the data in a comparison involving I (number of) laboratories are consistent provided that

$$R_B < \sqrt{1 + \sqrt{8/(I-1)}}$$

If the check fails, calculate the En values for all laboratories, remove the result with the largest En from contributing to the weighted mean, then re-iterate until the test is passed.

$$E_n = \frac{x_i - \bar{x}_w}{\sqrt{[U(x_i)]^2 - [U(\bar{x}_w)]^2}}$$

Any results no longer contributing to the weighted mean are no longer correlated so the uncertainty of their difference from the mean uses a '+' sign:

$$u(x_i - \bar{x}_w) = \sqrt{[u(x_i)]^2 + [u(\bar{x}_w)]^2}$$

“dark uncertainty” - dispersion of results > expected from lab uncertainties?

- ◆ Yes – this sometimes occurs
- ◆ Analytically confirmed by Birge Ratio being exceeded
- ◆ Sometimes a check on artefact drift is positive and this must then be taken into account
- ◆ Sometimes correlated with high *En* values for one or more measurands – suggesting artefact-specific problem
- ◆ In one comparison (*), detailed analysis revealed an uncertainty contribution never considered before in many decades of use!

Underpinning of CMCs by comparisons: step 1

◆ Determining "how far the light shines" : step 1 - skills matrix

Principal Techniques	CCL-K1	CCL-K2	CCL-K3		CCL-K4	CCL-K5		CCL-K6	CCL-K7	CCL-K8
	gauge block	length bar	poly	gau.	diameter	ball	step	2D CMM	linescale	surf tex.
Realizing the Metre definition										
Interferometry	2	2			2	2		2	2	1
Wavelengths in air	2	2			2	2		2	2	1
Gauge Issues										
Temperature of Gauge	1	2			2	2		2	2	1
Mounting & Aligning	1	2	2		2	2		2	2	1
Wavefront Probing										
Reflection Phase Effects	2	1								
Wringing	2	1								
Mechanical Probing										
Stylus contacting at surface, 1-D					2	1	2	1		2
Bi-directional probing for size					2		2			
Probing for 3-D center coordinates						2		2		
Image Probing										
Sensing Line Centres									2	
Angle Metrology										
Measuring small angles (autocoll.)			1	2						
Large Angle Gen: Circle Dividers			2	1				1		
Small Angle Gen: SineBar, CircDiv.				2						
Formal mathematical processing of data sets										
ISO parameter extraction										2
Form Metrology										
Flatness										1
Roundness					1					
Thread, Gear Profile										
3-D Surface										1

From CCL Strategy Document

Skills matrix from early days of MRA

2 = strong test of skill by comparison

1 = weaker test of skill

0 = no link

One comparison may test a skill that underpins several CMCs

Underpinning of CMCs by comparisons: step 2

- ◆ Pragmatic approach
- ◆ Use all positive evidence available:
 - Quality System (internal comparisons, cross-checks)
 - Comparisons evidence (where available)
 - DimVIM (similar classes of CMCs have similar skills)
 - Published papers in journals describing technique and testing
 - EURAMET: CMC review experts (usually KC pilots of similar topics)
 - **Blind comparison using commercial calibration to get a reference**

CMC formatting for CCL: DimVIM & GD-5

Column C, enter a short phrase that conveys the “Instrument Type or Method” used to make the measurement. The phrase should suggest (to an expert) the main scale, how the gauging features are probed, and any differential scale. These factors, combined with the identification of the reference standards used (Column L), tell an expert much about your procedure. Examples:

Artifact: Measurand

gauge blocks: central length

stage micrometer: line spacing

index table: angle

Instrument Type or Method

interferometry, exact fractions

video microscope & 1-D comparator

index table & one autocollimator

Reference Used

stabilized lasers

length interferometer

index table, autocollimator

- ♦ Avoid zero (minimum) or non-specified maximum in ranges (unless true!)
- ♦ Use of the **Q[a, bL] short form** notation for quadrature sum (root sum square)

Quantity equations vs numerical value equations

The KCDB currently uses *numerical value equations* for CMC uncertainties:

$$U = (25 + 1.2 L) \text{ nm}, L \text{ in mm}$$

Many accreditation bodies require the use of *quantity equations*:

$$U = 25 \text{ nm} + 1.2 \times 10^{-6} L$$

Raised for discussion under KCDB 2.0

Outline

- ◆ Introduction to CCL
- ◆ MRA: Organisational aspects within CCL
- ◆ MRA: Technical aspects within CCL
- ◆ Summary of key points

Key points (1/2)

- ◆ Slight bending of the rules to save time and money 😊
 - Not always KCRV
 - No mutual DoEs
 - Minimal numerical linking of comparisons
 - Not always '*classical*' comparison scheme, Inter-RMO used as well
- ◆ Organise and structure CC & WGs to achieve efficiency
 - Ensure good communications with the RMO TCs
 - Maximise use of experience, encourage new members
- ◆ Be flexible and put some trust in quality systems & experts
- ◆ Use template documents/Excel files to make things easy for pilots

Key points (2/2)

- ◆ Expect delays in some (all?) comparisons
- ◆ Be as open & inclusive as possible
 - Guidance documents, Final Reports, Strategy, Planning, Templates,
- ◆ Provide feedback to:
 - ◆ Strategy WG - Issues may show need for new research
 - ◆ WG-MRA (via RMO TC chairs) – willing to help you
 - ◆ Discussion Groups (anyone can be a member) – talk about experiences
- ◆ Ask for help – either someone has done it before or we can learn something new together!



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<http://www.bipm.org/wg/AllowedDocuments.jsp?wg=CCL-WG>

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Image credits

metre bar & laser - A Lewis, UK.

meeting of the CCL – (<http://www.bipm.org/jsp/en/CCPicture.jsp?cc=CCL>) BIPM.

meeting of the CCL WG-MRA 2017 – VTT-MIKES

part & engineering drawing - NPL, UK; *Si sphere* - PTB, DE; *Boltzmann resonator* - NPL UK; *Airbus wing* – M McCarthy, UK; *gear* – NimTECH workshop presentation R Thalmann, METAS, CH (http://www.nimtech.ptb.de/nimtech/fileadmin/documents/nimtech/pdf/Keynote_Thalmann.pdf); *nanomark* - Industrial Development Bureau, Ministry of Economic Affairs, TW (<http://www.nanomark.org.tw/Eng/>).

ion trap – NPL, UK; *freeform scanner* – NPL, UK; *aero engine* – NPL, UK; *gauge blocks* – NPL, UK; *XCT image of turbine blade* – Nikon Corporation (http://www.nikon.com/products/industrial-metrology/lineup/xray_ct/ct/xth450/index.htm); *Si X-ray Interferometer* – NPL, UK.

part & engineering drawing - NPL, UK; *Gauge Block Interferometer* – NPL, UK; *KCDB extracts* – BIPM; *gauge comparator* – Willrich Precision (<https://willrich.com/product/tesa-upd-gauge-block-comparators/>); *gauge on tool* – Frank Ford, US, (<http://www.frets.com/HomeShopTech/Tooling/LatheSineFixture/sinefixture05.jpg>); *gauge block set* – NPL, UK; *API thread gauges* – NPL, UK.

CCL Working Group schematic diagram – A Lewis, NPL, UK & CCL WG-MRA.

extract from DimVIM – sWG-CMC of the CCL WG-MRA.

skills matrix extract from CCL Strategy document – CCL WG-S and CCL WG-MRA.

inter-RMO comparison scheme – CCL WG-MRA.

comparison topic K1 planning sheet – CCL-WG-MRA.

CCL-K11 graph – M Matus, BEV, AT & KCDB, BIPM.

length comparisons Excel sheet – A Lewis, NPL, UK.

EURAMET.L-K1.2011 graph – M Matus, BEV, AT.

EURAMET.L-K1.2011 transport boxes – M Matus, BEV, AT;

mathematics - from WG-MRA Guidance Documents, A Lewis & CCL WG-MRA.

skills matrix extract from CCL Strategy document, ibid.